THIRD WORKSHOP ON THIN FILM PHYSICS AND TECHNOLOGY, including TOPICAL CONFERENCE ON MICROSTRUCTURE AND SURFACE MORPHOLOGY EVOLUTION IN THIN FILMS (REPOSITORY FOR LECTURE NOTES FROM THE SCANNED HISTORICAL ARCHIVE) | (smr 1135)

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STRUCTURAL CHARACTERIZATION OF INTERFACES WITH X-RAY PHOTOELECTRON DIFFRACTION

Content

Summary

Primary author(s) : T. GREBER

Presenter(s) : T. GREBER